FETKY™ Power MOSFET and Schottky Diode

-20 V, -3.3 A P-Channel with 20 V, 1.0 A Schottky Diode, Micro8™ Package

The FETKY product family incorporates low $R_{DS(on)}$, true logic level MOSFETs packaged with industry leading, low forward drop, low leakage Schottky Barrier Diodes to offer high efficiency components in a space saving configuration. Independent pinouts for TMOS and Schottky die allow the flexibility to use a single component for switching and rectification functions in a wide variety of applications.

Features

- Low V_F and Low Leakage Schottky Diode
- Lower Component Placement and Inventory Costs along with Board **Space Savings**
- Logic Level Gate Drive Can be Driven by Logic ICs
- Pb-Free Package is Available

Applications

- Buck Converter
- Synchronous Rectification
- Low Voltage Motor Control
- Load Management in Battery Packs, Chargers, Cell Phones, and other Portable Products

MOSFET MAXIMUM RATINGS ($T_A = 25$ °C unless otherwise noted)

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Rat	ing		Symbol	Value	Unit			
Drain-to-Source Volta	ige		V_{DSS}	-20	V			
Gate-to-Source Volta	ge		V_{GS}	-10	V			
Continuous Drain		T _A = 25°C	I_{D}	3.3	Α			
Current (Note 1)		T _A = 100°C		2.1				
Power Dissipation (Note 1)	Steady State	T _A = 25°C	P _D	1.42	W			
Continuous Drain		T _A = 25°C	I_{D}	2.4	Α			
Current (Note 2)		T _A = 100°C		1.5	1			
Power Dissipation (Note 2)	Steady State	T _A = 25°C	P _D	0.78	W			
Pulsed Drain Current	t =	: 10 μs	I _{DM}	10	Α			
Operating Junction and Storage Temperature		T _J , T _{STG}	–55 to 150	°C				
Single Pulse Drain-to-Source Avalanche Energy Starting $T_A = 25^{\circ}C$ (t \leq 10 s)		EAS	150	mJ				
Lead Temperature for (1/8" from case for		Purposes	TL	260	°C			

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Surface-mounted on FR4 board using 1 in sq pad size
- (Cu area = 1.127 in sq [1 oz] including traces).

 2. Surface–mounted on FR4 board using the minimum recommended pad size (Cu area = 0.172 in sq).



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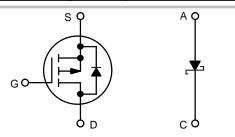
http://onsemi.com

MOSFET PRODUCT SUMMARY

V _{(BR)DSS}	R _{DS(on)} Typ	I _D Max
–20 V	70 mΩ @ –4.5 V	-3.3 A
	100 mΩ @ –2.7 V	–2.7 A

SCHOTTKY DIODE SUMMARY

V _R Max	I _F Max	V _F Max
20 V	2.0 A	600 mV @ I _F = 2.0 A

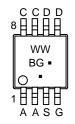


P-Channel MOSFET

Schottky Diode

MARKING DIAGRAM & PIN ASSIGNMENT





BG = Specific Device Code WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]		
NTTD4401FR2	Micro8	4000/Tape & Reel		
NTTD4401FR2G	Micro8 (Pb-Free)	4000/Tape & Reel		

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

SCHOTTKY DIODE MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Reverse Voltage	V	20	V
Average Forward Current (Rated V _R , T _A = 100°C)	Io	1.0	Α
Peak Repetitive Forward Current (Note 3)	I _{FRM}	2.0	Α
Non–Repetitive Peak Surge Current (Note 4)	I _{FSM}	20	Α

THERMAL RESISTANCE RATINGS

		FET Schottky		
Rating	Symbol	Ma	ax	Unit
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	88	135	°C/W
Junction-to-Ambient - Steady State (Note 6)	$R_{\theta JA}$	160	250	°C/W

$\textbf{MOSFET ELECTRICAL CHARACTERISTICS} \ (T_{A} = 25^{\circ}\text{C unless otherwise noted})$

Characteristic	Symbol	Test Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	-			-		-
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V	-20	_	_	V
Zero Gate Voltage Drain Current (Note 7)	I _{DSS}	$V_{GS} = 0 \text{ V}, V_{DS} = -16 \text{ V}$	-	_	-1.0	μΑ
		V _{GS} = 0 V, T _J = 125°C, V _{DS} = -16 V	1	_	-25	1
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 10 \text{ V}$	_	_	±100	nA
ON CHARACTERISTICS						
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.5	-	-1.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	-	-	2.5	-	mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -3.3 \text{ A}$	_	70	90	mΩ
		$V_{GS} = -2.5 \text{ V}, I_D = -1.2 \text{ A}$	_	100	150	1
Forward Transconductance	9FS	$V_{DS} = -10 \text{ V}, I_D = -2.7 \text{ A}$	1	4.2	-	S
CHARGES, CAPACITANCES AND GATE	RESISTANCE					
Input Capacitance	C _{ISS}		-	550	750	pF
Output Capacitance	C _{OSS}	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = -16 \text{ V}$	1	200	300	
Reverse Transfer Capacitance	C _{RSS}	V _{DS} = -16 V		50	175	1
Total Gate Charge	Q _{G(TOT)}		1	10	18	nC
Gate-to-Source Gate Charge	Q_{GS}	$V_{GS} = -4.5 \text{ V}, V_{DS} = -16 \text{ V},$ $I_{D} = -3.3 \text{ A}$	_	1.5	3.0	1
Gate-to-Drain "Miller" Charge	Q_{GD}]	_	5.0	10	1
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t _{d(ON)}		_	11	20	ns
Rise Time	t _r	$V_{GS} = -4.5 \text{ V}, V_{DD} = -10 \text{ V},$	-	35	65	1
Turn-Off Delay Time	t _{d(OFF)}	$I_D = -3.3 \text{ A}, R_G = 6.0 \Omega$	1	33	60	1
Fall Time	t _f		-	29	55	1
DRAIN-SOURCE DIODE CHARACTERIS	TICS					
Forward Diode Voltage	V _{SD}	$V_{GS} = 0 \text{ V, } I_{S} = -2.0 \text{ A}$	-	-0.88	-1.0	V
Reverse Recovery Time	t _{RR}		-	37	50	ns
Charge Time	ta	$V_{GS} = 0 \text{ V, } d_{IS}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = -3.3 \text{ A}$	-	16	-	1
Discharge Time	t _b]	-	21	-	1
Reverse Recovery Charge	Q_{RR}	-	-	0.025	0.05	nC

- Rated V_R, square wave, 20 kHz, T_A = 105°C.
 Surge applied at rated load conditions, half-wave, single phase, 60 Hz.
 Surface-mounted on FR4 board using 1 inch sq pad size (Cu area = 1.127 in sq [1 oz] including traces).
 Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.172 in sq).
 Body diode leakage current.

SCHOTTKY DIODE ELECTRICAL CHARACTERISTICS ($T_J = 25$ °C unless otherwise noted)

Characteristic	Symbol	Test Condition		Min	Тур	Max	Unit
Reverse Breakdown Voltage	B _V	I _R = 1.0 mA		20	-	-	V
Reverse Leakage Current	I _R	V 20 V	T _A = 25°C	-	-	0.05	mA
		V _R = 20 V	T _A = 125°C	_	-	10	
Forward Voltage	V _F	1 101	T _A = 25°C	-	-	0.5	V
		I _F = 1.0 A	T _A = 125°C	_	-	0.39	
		1 204	T _A = 25°C	_	-	0.6	
		$I_F = 2.0 \text{ A}$	T _A = 125°C	_	-	0.53	
Voltage Rate of Change	dV/dt	V _R = 20 V		_	10,000	-	V/μs

TYPICAL ELECTRICAL CHARACTERISTICS

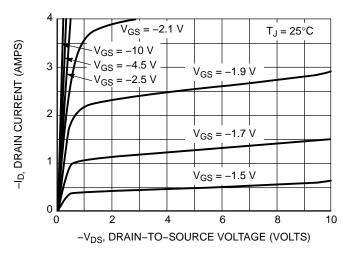
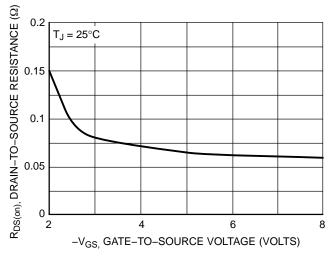


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



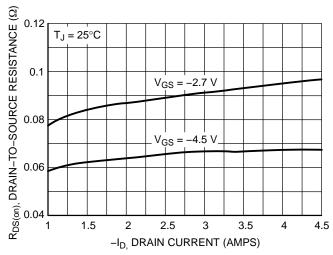
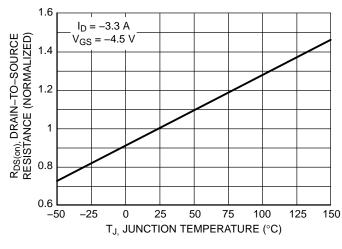


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On–Resistance vs. Drain Current and Gate Voltage



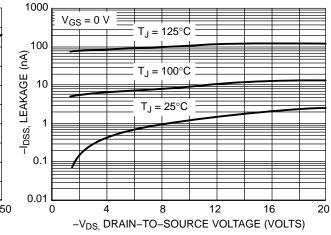
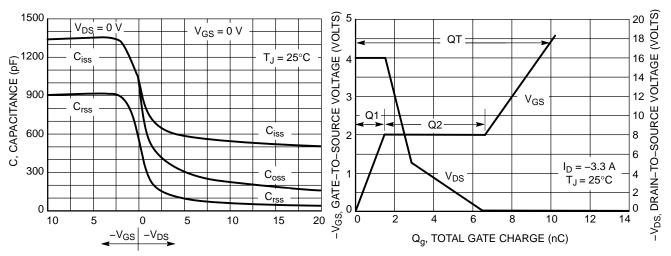


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL ELECTRICAL CHARACTERISTICS



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

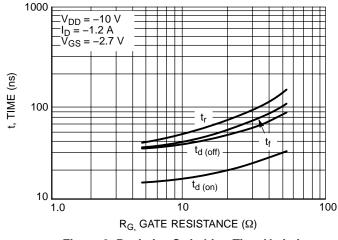


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

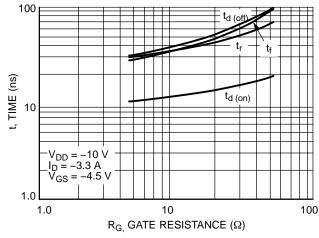


Figure 10. Resistive Switching Time Variation vs. Gate Resistance

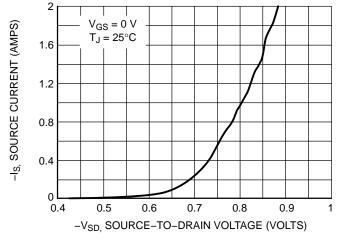


Figure 11. Diode Forward Voltage vs. Current

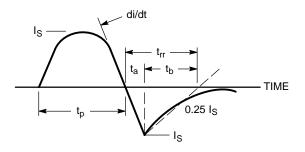


Figure 12. Diode Reverse Recovery Waveform

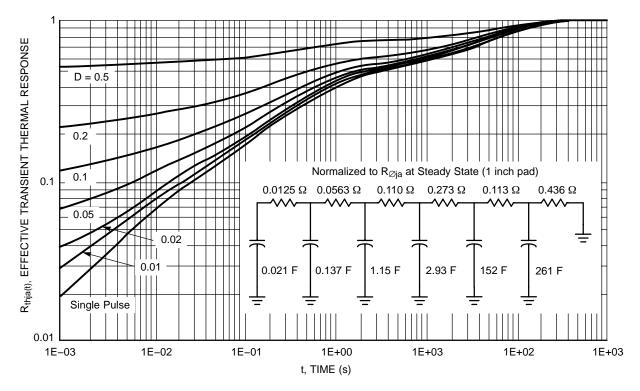


Figure 13. FET Thermal Response

TYPICAL SCHOTTKY ELECTRICAL CHARACTERISTICS

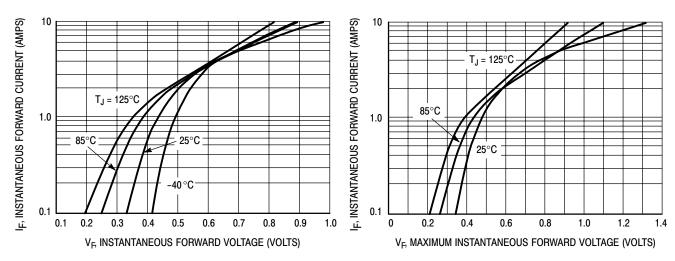


Figure 14. Typical Forward Voltage

Figure 15. Maximum Forward Voltage

TYPICAL SCHOTTKY ELECTRICAL CHARACTERISTICS

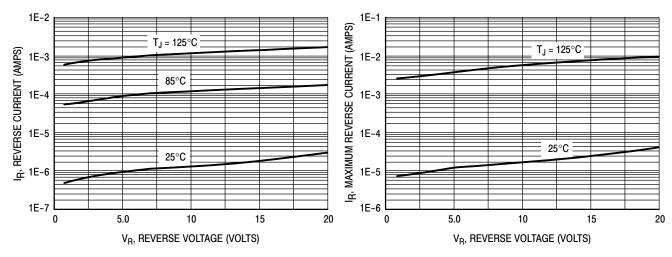


Figure 16. Typical Reverse Current

Figure 17. Maximum Reverse Current

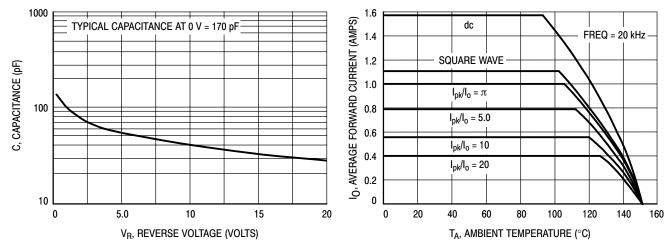


Figure 18. Typical Capacitance

Figure 19. Current Derating

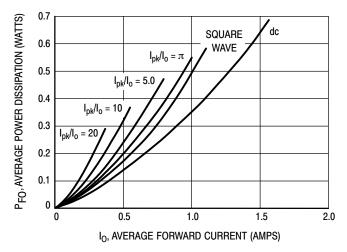
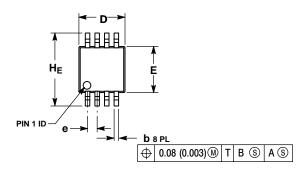
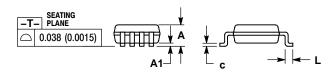


Figure 20. Forward Power Dissipation

PACKAGE DIMENSIONS

Micro8™ CASE 846A-02 ISSUE G



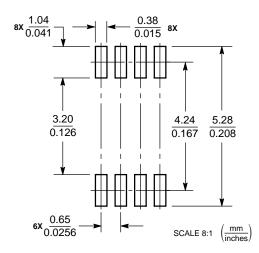


NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE
- DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE. 846A-01 OBSOLETE, NEW STANDARD 846A-02.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α			1.10			0.043	
A1	0.05	0.08	0.15	0.002	0.003	0.006	
b	0.25	0.33	0.40	0.010	0.013	0.016	
С	0.13	0.18	0.23	0.005	0.007	0.009	
D	2.90	3.00	3.10	0.114	0.118	0.122	
E	2.90	3.00	3.10	0.114	0.118	0.122	
е		0.65 BSC		0.026 BSC			
L	0.40	0.55	0.70	0.016	0.021	0.028	
HE	4.75	4.90	5.05	0.187	0.193	0.199	

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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